

L Number	Hits	Search Text	DB	Time stamp
1	0	(5404358.pn.) and chain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 13:58
2	1	(5404358.pn.) and serial\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:02
3	1	(5404358.pn.) and serial\$2 and switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:14
4	5	(second adj scan adj register\$1) and chain\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:39
5	35	scan adj register\$1 adj chain\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:05
6	1	(scan adj register\$1 adj chain\$1) with bypass\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:20
7	93	(scan adj chain\$1) with bypass\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:21
8	36	(scan adj chain\$1) with register with bypass\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 16:25
9	0	(scan adj chain\$1) with bypass\$3 with switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:26
10	3	(scan with chain\$1) with bypass\$3 with switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:27
11	2	((scan with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:28
12	4	((register with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:29
13	2	5491666.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 17:39
14	3	6708304.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 17:39

-	2	20020144200.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:46
-	0	(714/726.pn.) and scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:50
-	13	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/05 15:59
-	4	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output) and (short with wiring)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:00
-	2	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output) and (analog with wiring)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:01
-	6	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output) and (analog with input)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:06
-	2	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and (internal adj circuit) and pin\$1 and (scan adj register\$1) and (input adj output) and (analog with pin\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 11:07
-	32	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and pin\$1 and (scan adj register\$1) and (input adj output) and (analog with pin\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:35
-	22	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and pin\$1 and (scan adj register\$1) and (input adj output) and (analog with pin\$1) and (JTAG with scan\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:28
-	2	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and pin\$1 and ((scan adj register\$1) with ((input adj output) adj pin)) and (analog with pin\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 14:56
-	2	5322989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:58
-	0	JP05322989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:59
-	0	JP5322989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 15:59

-	1	05322989.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:01
-	112834	TORU.INV.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:02
-	112834	TORU.IN.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:02
-	0	TORU-SHIONO.IN.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:03
-	2	TORU-SH\$4.IN.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:03
-	0	TORU-SHIONO.IN.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:06
-	2	11038091.PN.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:06
-	2	20020144200.pn.	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 16:36
-	144	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and (scan adj register\$1) and (JTAG with scan\$4 with register)	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:29
-	41	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and (scan adj register\$1) and (JTAG with scan\$4 with register) and (JTAG with specification)	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:30
-	9	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and (scan adj register\$1) and (JTAG with scan\$4 with register) and (JTAG with specification) and (register with chain) and (control\$3 with (scan adj register))	USPÄT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:35
-	1	scan\$4 and test\$3 and (semiconductor\$1 or (integrated adj circuit\$1) or IC) and (scan adj register\$1) and (JTAG adj (scan\$4 adj register)) and (JTAG with specification) and (register with chain) and (control\$3 with (scan adj register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/08 17:35